

# ONE-STOP TEST DEVELOPMENT AND TEST INTERFACE SOLUTIONS



## ATS300 | Analog & PMIC

- ❑ **All-in-One Test Head:** Combining analog AWG/Digitizer VI sources, and Digital/Timing channels.
- ❑ **High-Channel Density:** 36 slots for flexible analog and digital configurations.
- ❑ **Multi-Parallelism:** Optimized for testing multiple devices at once, speeding up productions.

## ATS200 | Analog, Power Discrete & IPM/PIM

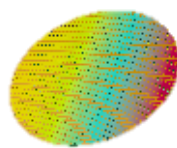
- ❑ **High-Power DC Testing:** Supports up to 2000V and  $\pm 200A$ , with an upgrade option to 3600V and  $\pm 600A$  for greater flexibility.
- ❑ **Expandable Dynamic AC Testing:** Switching, Short Circuit, Avalanche, Thermal Resistance, and  $C_g$ ,  $R_g$  measurements with integrated data logging.



ATS300



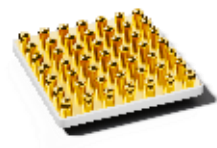
ATS200



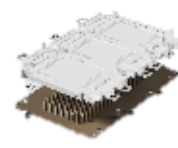
PMIC Wafer



PMIC



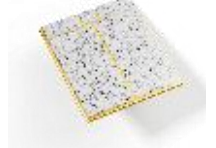
Mobile PMIC



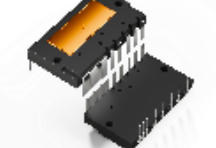
Power Module



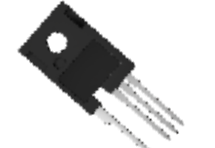
DSC



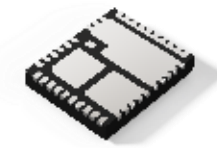
KGD



IPM



MOSFET/IGBT/SiC

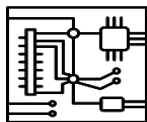


DrMos (SPS)



# ONE-STOP TEST DEVELOPMENT AND TEST INTERFACE SOLUTIONS

## TEST ENGINEERING SERVICES



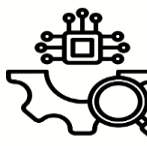
### New Product Test Development

- Hardware Design & Fabrication  
Loadboard, Probe Cards, Test Jig  
PCB Layout & Hardware Assembly, Test Socket,  
Stiffener & Fixture etc.
- Software Program  
Test Development & Debugging  
Device Test Plan/Design of Test Methodologies  
Test Time Optimization  
On-site Release of Hardware & Test Program



### Manufacturing Improvements

- Yield Improvement
- Multisite Conversion
- Test Time Optimization
- Engineering Management & On-Site Support



### ATE Platform Conversion & In-house ATE Platform:



ATS200



ATS300



Advantest V93K



Teradyne ETS364B



Teradyne ETS88



Accotest STS8300



[www.jf-technology.com](http://www.jf-technology.com)

## TALENT DEVELOPMENT



Up-skill industry engineers with customized Training



Partnership with local Universities



Internship



## TEST INTERFACE PRODUCTS



Handler Docking Plate

Test Sockets

Probe Card

Pogo Tower

DUT Board

Stiffener

Docking Mechanism

Tester Docking Plate



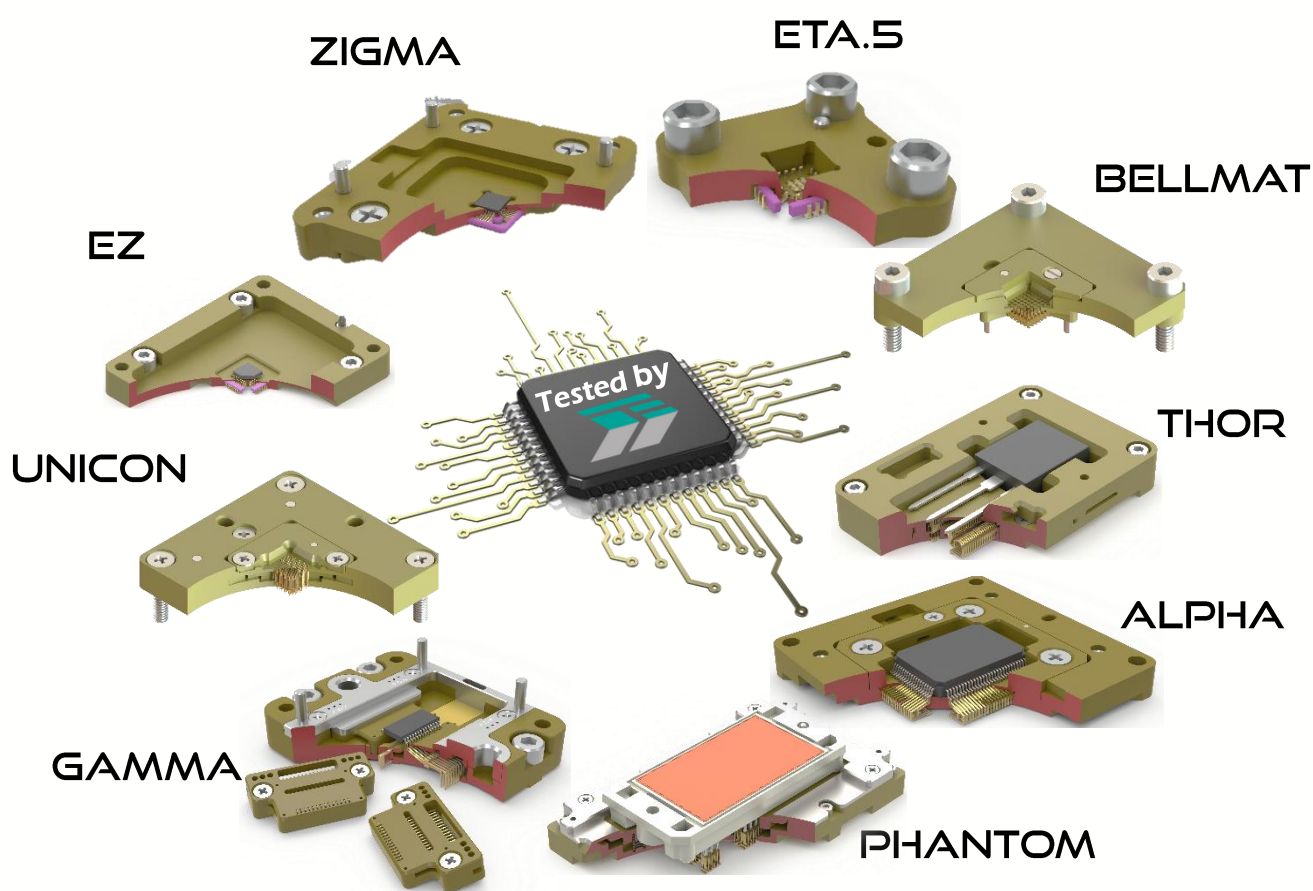
Tester



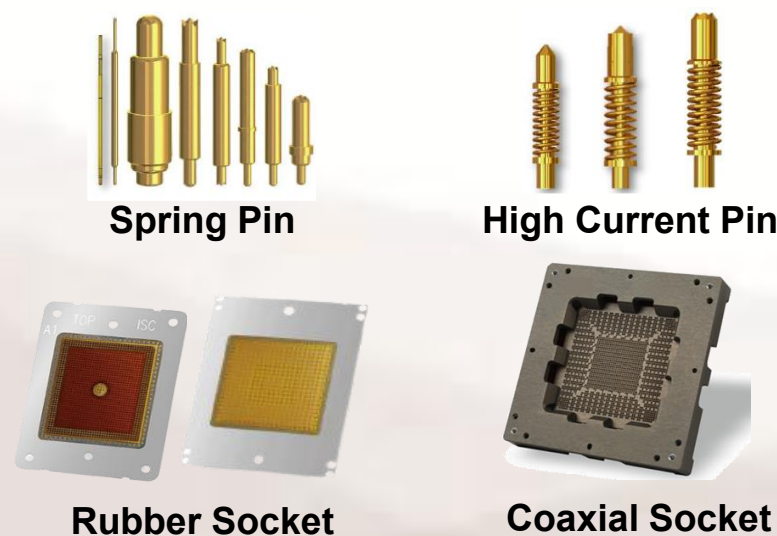
Manipulator

# ONE-STOP HIGH PERFORMANCE TEST CONTACTING SOLUTIONS

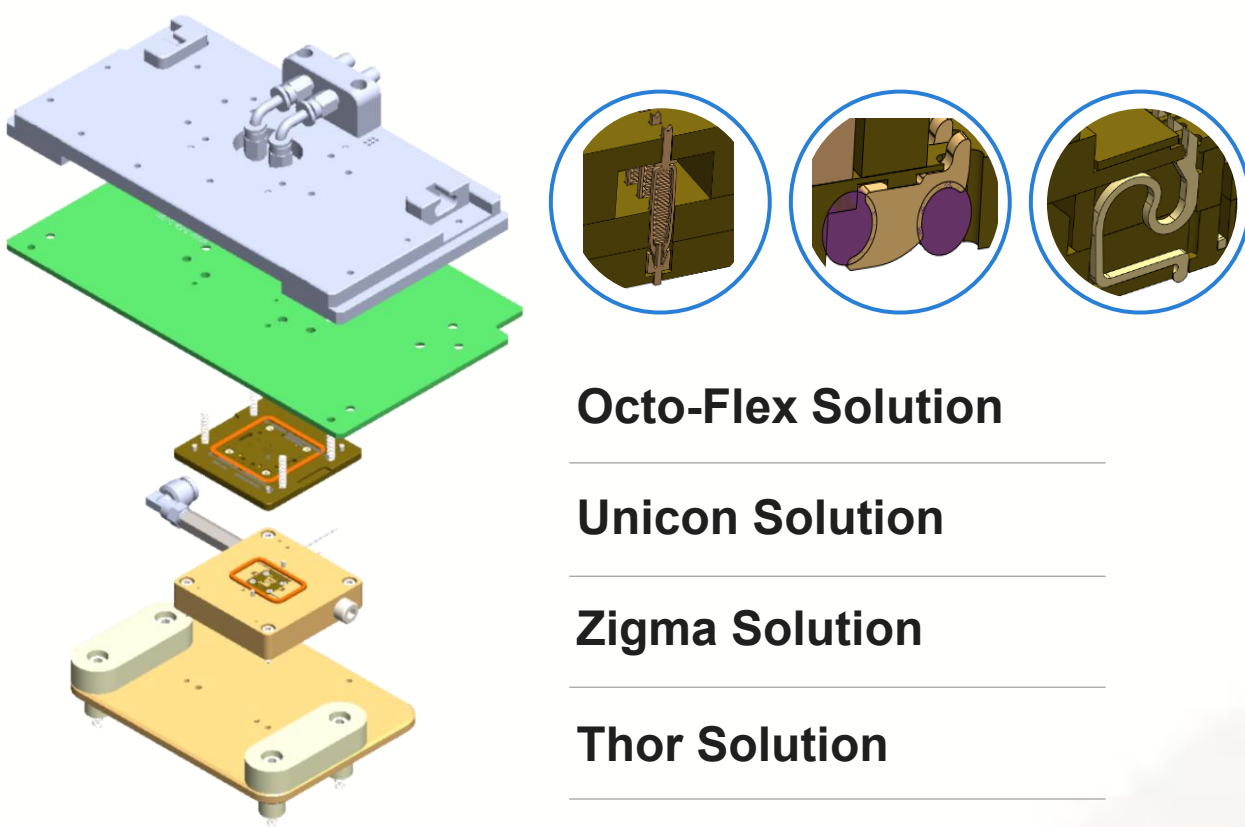
## TEST CONTACTING SOLUTIONS



## SPRING PROBE / COAXIAL



## KNOWN GOOD DIE (KGD)



## ELECTRICAL SIMULATION SERVICES

- Full-link Simulation
- Socket Design Optimization
- TDR Plot – Impedance Matching
- Load Board Design & Optimization
- S-Parameter
- E-field Analysis

